

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/834,618 ABE ET AL.	
		Examiner	Art Unit	Page 1 of 1 Sunray Chang 2121

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,067,582	05-2000	Smith et al.	710/5
	B	US-2002/0029242	03-2002	Seto, Satoshi	709/203
	C	US-6,347,333	02-2002	Eisendrath et al.	709/217
	D	US-6,014,651	01-2000	Crawford, Christopher M.	705/400
	E	US-6,180,862	01-2001	Hirano, Masashi	84/601
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.